SN54ALS33A, SN74ALS33A **QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS** WITH OPEN-COLLECTOR OUTPUTS SDAS034B - APRIL 1982 - REVISED DECEMBER 1994

Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

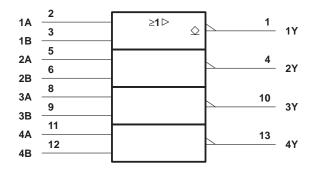
description

These devices contain four independent 2-input positive-NOR buffers with open-collector outputs. Open-collector outputs require resistive pullup to perform correctly. They can deliver higher VOH levels and commonly are used in wired-AND applications. These devices perform the Boolean functions $Y = \overline{A} \bullet \overline{B}$ or $Y = \overline{A + B}$ in positive logic.

The SN54ALS33A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS33A is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)							
INP	UTS	OUTPUT					
Α	В	Y					
н	Х	L					
Х	Н	L					
L	L	н					

logic symbol[†]

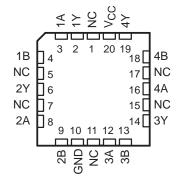


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

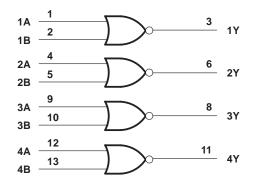
SN54ALS33A J PACKAGE SN74ALS33A D OR N PACKAGE (TOP VIEW)									
_		υ	L						
1Y [1	14	l v _{cc}						
1A 🛛	2	13] 4Y						
1B [3	12]4B						
2Y [4	11]4A						
2A [5	10]3Y						
2B [6	9] 3B						
GND [7	8] 3A						
l			l						

SN54ALS33A ... FK PACKAGE (TOP VIEW)



NC - No internal connection

logic diagram (positive logic)



PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Input voltage, V _I		7V
Off-state output voltage		
Operating free-air temperature range, TA:	: SN54ALS33A	55°C to 125°C
	SN74ALS33A	0°C to 70°C
Storage temperature range		65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS33A			SN74ALS33A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V	
VIH	High-level input voltage	2			2			V	
VIL	Low-level input voltage			0.7			0.8	V	
VOH	High-level output voltage			5.5			5.5	V	
IOL	Low-level output current			12			24	mA	
TA	Operating free-air temperature	-55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	тес	TEST CONDITIONS		SN54ALS33A			SN74ALS33A		
PARAMETER			MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lj = -18 mA			-1.5			-1.5	V
	V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
V _{OL}		I _{OL} = 24 mA					0.35	0.5	V
Ц	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
IН	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
١ _{IL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.1	mA
ЮН	V _{CC} = 4.5 V,	V _{OH} = 5.5 V			0.1			0.1	mA
Іссн	V _{CC} = 5.5 V,	$V_{I} = 0$		1.7	2.8		1.7	2.8	mA
ICCL	V _{CC} = 5.5 V,	V _I = 4.5 V		5.6	9		5.6	9	mA

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 4.5 V \text{ to } 5.5 V,$ $C_L = 50 \text{ pF},$ $R_L = 680 \Omega,$ $T_A = \text{MIN to MAX}$ $SN54ALS33A SN74ALS33A$ $MIN MAX MIN MAX$				UNIT
tPLH	A or B	Y	10	59	10	33	
^t PHL	A OF B		2	18	2	12	ns

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES 7 V $R_{L} = R1 = R2$ Vcc ረ **S1** ≶ RL ≶ R1 From Output Test From Output From Output Test Test **Under Test** Point Under Test Point Point **Under Test** CL Cı RL 3 R2 CL (see Note A) (see Note A) (see Note A) LOAD CIRCUIT FOR LOAD CIRCUIT LOAD CIRCUIT **BI-STATE TOTEM-POLE OUTPUTS** FOR OPEN-COLLECTOR OUTPUTS FOR 3-STATE OUTPUTS 3.5 V 3.5 V Timing **High-Level** 1.3 V 1.3 V 1.3 V Input Pulse 0.3 V 0.3 V th t_{su} 3.5 V 3.5 V Data Low-Level ٧ 1.3 V 1.3 V 1.3 V Input Pulse 0.3 V 0.3 V **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS** SETUP AND HOLD TIMES PULSE DURATIONS 3.5 V Output Control 1.3 V .3 V (low-level 0.3 V enabling) 3.5 V ^tPZL 1.3 V 1.3 V Input ^tPLZ 0.3 V 3.5 V - tPHL Waveform 1 tpi H 1.3 V S1 Closed VOH In-Phase (see Note B) 1.3 V 1.3 V VOL Output Vol 0.3 V ^tPHZ ^tPLH tPZH -tPHL -۷он Waveform 2 Vон Out-of-Phase S1 Open 1.3 V 1.3 V 0.3 V Output (see Note B) VoL (see Note C) 0 V **VOLTAGE WAVEFORMS** VOLTAGE WAVEFORMS **PROPAGATION DELAY TIMES ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS** NOTES: A. CL includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

- When measuring propagation delay items of 3-state outputs, switch S1 is open. C.
- All input pulses have the following characteristics: PRR \leq 1 MHz, t_r = t_f = 2 ns, duty cycle = 50%. D. E.
- The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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